Product Name	Fanless Touch Panel
Model Number	xxxxxAHP-2122HTT -xxxxxxxx
	(Where x is 0-9 · A-Z · -or blank) for marketing purpose
Applicant	AAEON Technology Inc.
Address	5F,NO.135,Lane 235,Pao Chiao Rd. Hsin-Tien Dist,New Taipei
	City, Taiwan, R.O.C.
Report Number	F-U070-1111-223
Issue Date	: December 6, 2011
Applicable Standards	FCC Part 15, Subpart B Class A ITE ANSI C63.4:2003

One sample of the designated product has been tested in our laboratory and found to be in compliance with the FCC rules cited above.

CSA-IEC CISPR22: 02 Class A ITE





NVLAP LAB CODE 200575-0

TAF 0905 FCC CAB Code TW1053 IC Code 4699A VCCI Accep. No. R-1527, C-1609, T-1441, G-10



Central Research Technology Co. EMC Test Laboratory 11, Lane 41, Fushuen St., Jungshan Chiu, Taipei, Taiwan, 104, R.O.C. Tel : 886-2-25984568 Fax: 886-2-25984546

J. Y. Ell

(Tsun-Yu Shih/General Manager) Date: <u>December 6, 2011</u>

FCC Test Report

for

Fanless Touch Panel

Model Number	:	xxxxxAHP-2122HTT –xxxxxxxx
		(Where x is 0-9 , A-Z , -or blank) for
		marketing purpose
Report Number	:	F-U070-1111-223
Date of Receipt	:	November 21, 2011
Date of Report	:	December 6, 2011

Prepared for

AAEON Technology Inc.

5F,NO.135,Lane 235,Pao Chiao Rd. Hsin-Tien Dist,New Taipei City,Taiwan,R.O.C.



11, Lane 41, Fushuen St., Jungshan Chiu, Taipei, Taiwan, 104, R.O.C.



NVLAP LAB CODE 200575-0

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Verification of Compliance

Equipment Under Test	:	Fanless Touch Panel			
Model No.	:	xxxxxAHP-2122HTT –xxxxxxxx			
		(Where x is 0-9 , A-Z , -or blank) for marketing purpose			
Applicant	:	AAEON Technology Inc.			
Address	:	5F,NO.135,Lane 235,Pao Chiao Rd. Hsin-Tien Dist,New			
		Taipei City,Taiwan,R.O.C.			
Applicable Standards	:	FCC Part 15, Subpart B Class A ITE			
		ANSI C63.4:2003			
		Industry Canada ICES-003 Issue 4			
		Industry Canada ICES-003 Issue 4			
		Industry Canada ICES-003 Issue 4 CSA-IEC CISPR22: 02 Class A ITE			
		Industry Canada ICES-003 Issue 4 CSA-IEC CISPR22: 02 Class A ITE			
Date of Testing	:	Industry Canada ICES-003 Issue 4 CSA-IEC CISPR22: 02 Class A ITE November 21~30, 2011			
Date of Testing Deviation	:	Industry Canada ICES-003 Issue 4 CSA-IEC CISPR22: 02 Class A ITE November 21~30, 2011			

We, **Central Research Technology Co**., hereby certify that one sample of the designated product was tested in our facility during the period mentioned above. The test records, data evaluation and Equipment Under Test (EUT) configurations shown in the present report are true and accurate representation of the measurements of the sample's EMC characteristics under the conditions herein specified.

The test results show that the EUT as described in the present report is in compliance with the requirements set forth in the standards mentioned above and apply to the tested sample identified in the present report only. The test report shall not be reproduced, except in its entirety, without the written approval of Central Research Technology Co.

PREPARED BY	:	Rosa Hsief. (Rosa Hsieh/System Executive)	, DATE :	December E. 2011
APPROVED BY	:	J. Y. U.L. (Tsun-Yu Shih/General Manager	• DATE :	Dec. 6, 2011

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1. General Description

1.1 General Description of EUT

Equipment Under Test	:	Fanless Touch I	Pane	el
Model No.		xxxxxAHP-2122	Г —xxxxxxxx	
		(Where x is 0-9	, A-	Z, -or blank) for marketing
		purpose		
Power in	:	Supplied by the	pov	ver adapter
Power Adapter Specification	:	Trade Name	:	FSP
		Model Number	:	FSP084-DMAA1
		Input	:	100-240Vac, 1.3A, 50-60Hz
		Output	:	12Vdc, 7.0A Max(84W Max).
Highest Operating Frequency	:	1.8GHz from the	e tes	st specification
Manufacturer	:	AAEON Techno	ology	/ Inc.
Function Description	:			

The EUT is an engineering sample of the Fanless Touch Panel. Please refer to the user's manual for the details.

The Model Number AHP-2122HTT-A2-1010 was selected by its manufacturer to perform all tests. It was taken as the representative condition for test and its data are recorded in the present document.

The I/O ports of EUT are listed below:

No.	I/O Port Type	Quantity
1	D-Sub Port	1
2	USB Port	4
3	RS232 Port	2
4	LAN Port	2

The devices (supplied by the manufacturer) can be installed inside the EUT are listed below:

Components	Specification
M/D	AAEON GENE-LN05-xxxxxx
M/B	(Where x is 0-9 , A-Z , -or blank) for marketing purpose
CPU	Intel Atom D525 1.8GHz
HDD	TOSHIBA , MK1665GSX , 160GB
Memory	DSL , DDR3-1066 2GB/ELPIDA J1108BFBG-DJ-F
DC-DC Power Board	AAEON PER-P17D REV.B1.0
Touch Board	AAEON PER-T102 REV.A1.5
	FSP,Model:FSP084-DMAA1,O/P:12V/7A,84Watt
AC/DC Power Supply	EUT POWER RATING : 9-30VDC
OSC	32.768KHZ; 25MHZ;14.31818MHZ

1.2 Test Mode

Normal operating as the customer's requirement. The EUT was tested with display mode: 1024 x 768@60Hz and D-Sub 1024 x 768@60Hz.

1.3 Applied standards

According to the specifications of the manufacturer and the requirements set in 47CFR Part 15, the applied standards to evaluate the compliance of the EUT are as following, and the measurement procedures specified in ANSI C63.4: 2003 are performed.

According to 47CFR Part 15 Section 15.33(b), the test frequency range of radiated emission measurements are listed below and the EUT herein shall be tested as:

Type of EUT	Highest frequency generated or used in the device or on which the device operates or tunes (MHz)	Upper frequency of measurement range (MHz)
	Below 1.705	30
	1.705 - 108	1000
	108 - 500	2000
	500 - 1000	5000
		5 th harmonic of the highest
\checkmark	Above 1000	frequency or 40GHz,
		whichever is lower

All the test items are as following:

Applied Standards	Test Items	Results
FCC Part 15, Subpart B	☑ Conducted Emission Measurement	PASS
Class A ITE	☑ Radiated Emission Measurement	PASS

1.4 Test Setup for the EUT

The EUT is an unique unit connected with other necessary accessories and support units listed in the next section. It has been tested against each standard after the following setup steps:

- a. Connect the EUT and all the support units to the appropriate power source.
- b. Turn on the EUT and all the accessories and support units.
- c. Install an EMC test software into EUT and execute it under the Windows environment.
- d. The EUT sends "H" patterns to the display and monitor, which fills the whole screen of it.
- e. The EUT sends messages to the modems.
- f. The EUT reads/writes messages from/to the USB Flash Disk(s).
- g. Another PC sends/ receives messages to/ from the EUT through a Hub by executing the command of "PING".
- h. Repeat and keep setup steps listed above before and during all tests.

EUT I/O ports / Peripherals	Exerciser Program (software)	Version of Program	
EUT			
Monitor	BurnIn Test exe	V 6 0	
USB Flash Disk(s)			
Modem			

1.5 The Support Units

No.	Unit	Model No./ Serial No.	FCC ID	Trade Name	Power Cord	Supported by lab.
		2408WFP ^(Note 1) /				
	•••	CN-0NN792-74261- 849-154S	DoC	DELL	1.8m	~
	WORMON	U2410 ^(Note 2) /				
		CN-0J257M-72872- 083-069L	DoC	DELL	1.8m	~
2	USB Mouse	MOC5U0 / G1E03M10	DoC	DELL	N/A	~
3	USB Keyboard	SK-8815/ CN-0J4635-71616- 4BD-0M07	DoC	DELL	N/A	~
4 Modem	DM-1414/ 0311055094	IFAXDH1414	ACEEX	1.9m	~	
	Modern	DM-1414/ 0509019804	IFAXDH1414	ACEEX	1.9m	~
5	USB Flash Disk	U172/ 100-031	DoC	PQI	N/A	~
		U172/ 100-052	DoC	PQI	N/A	~

Note 1: Used for Conducted Emission Test.

Note 2: Used for Radiated Emission Test

1.6 Layout of the Setup



Connecting Cables :

No.	Cable	Length	Shielded	Core	Shielded Backshell	Supported by lab.	Note
А	VGA Cable	1.7m	~	\checkmark		\checkmark	2Cores
B USB Mouse Cable		1.8m	~			\checkmark	
С	C USB Keyboard Cable		~			\checkmark	
D	D Modem Cable		✓	✓		\checkmark	2Cores
Е	LAN Cable	>3m				\checkmark	

1.7 Test Capability

Test Facility

The test facility used for evaluating the conformance of the EUT with each standard in the present report meets what required in CISPR16-1-4, CISPR16-2-3 and ANSI C63.4: 2003.

Test Room	Type of Test Room	Descriptions	
TR1	10m semi-anechoic chamber ($23m \times 14m \times 9m$)	Complying with the NSA requirements in documents CISPR 22 and	
TR11	3m semi-anechoic chamber ($9m \times 6m \times 6m$)	ANSI C63.4: 2003. for the radiated emission measurement.	
TR5	Shielding Room (8m × 5m × 4m)	For the conducted emission measurement.	

Test Laboratory Competence Information

Central Research Technology Co. has been accredited / filed / authorized by the agencies listed in the following table.

Certificate	Nation	Agency	Code	Mark
	USA	NVLAP	200575-0	ISO/IEC 17025
	R.O.C.		0905	
	(Taiwan)		0903	130/120 17023
Accreditation			SL2-IN-E-0033,	
Certificate	POC		SL2-IS-E-0033,	
	(Taiwan)	BSMI	SL2-R1/R2-E-0033,	ISO/IEC 17025
	(Taiwaii)		SL2-A1-E-0033	
			SL2-L1-E-0033	
	1167	FCC	474046 TW1053	Test facility list &
	034	100	474040;1 00 10000	NSA Data
Site Filing	Canada	IC	46004 1 3	Test facility list &
Document	Callaua	2	+099A-1,-0	NSA Data
	lanan	VCCI	P 1527 C 1600 T 1441 C 10	Test facility list &
	Japan	VCCI	11-1327,6-1009,1-1441,6-10	NSA Data
Authorization	Germany	TUV	10021687	ISO/IEC 17025
Certificate	Norway	Nemko	ELA 212	ISO/IEC 17025

The copy of each certificate can be downloaded from our web site: www.crc-lab.com

2. Conducted Emission Measurement

Test Result : PASS

2.1 Limits for Emission Measurement

☑ Limits for conducted disturbances at the power mains

Frequency (MHz)	Class A E	quipment	Class B Equipment		
	Quasi-peak	Average	Quasi-peak	Average	
	(dBµV)	(dBµV)	(dBµV)	(dBµV)	
0.15 to 0.5	79	66	66 – 56	56 – 46	
0.5 to 5	73	60	56	46	
5 to 30	73	60	60	50	
Note 1- The lower limit shall apply at the transition frequency.					
Note 2- The limit decreases linearly with the logarithm of the frequency in the range 0.15 MHz to					
0.5MHz for Cla	ass B equipment.				

2.2 Test Instruments

Test Site and	Manufacturor	Model No./	Last	Calibration	
Equipment	Manufacturer	Serial No.	Calibration Date	Due Date	
Test Bessiver	DIS	ESCS 30/	lon 14 2011	lan 11 0010	
Test Receiver	Ras	836858/021	Jan. 14, 2011	Jan. 14, 2012	
LIGN	DIS	ESH2-Z5/	luno 2, 2011	lupo 2, 2012	
LISIN	ΓαΟ	836613/001	June 2, 2011	June 2, 2012	
	DIS	ENV4200/	lan 14 2011	lan 14 2012	
2 LISIN	Ras	833209/010	Jan. 14, 2011	Jall. 14, 2012	
500 torminator	NI/A	N/A/	Aug. 20, 2011	Aug. 20, 2012	
	N/A	001	Aug. 20, 2011		
DE Switch	Ν/Δ	RSU28/	Aug 20 2011	Eab 20 2012	
	N/A	338965/002	Aug. 20, 2011	Feb. 20, 2012	
DE Cabla	NI/A	N/A/	Aug. 20, 2011	Eab 20 2012	
	N/A	C0052 ~ 56	Aug. 20, 2011	red. 20, 2012	
Tost Softwara	Audix	e3/			
Test Soltware	Audix	Ver. 5.2004-2-19k	NCK	NCK	
TR5	ETS	TR5/			
shielded room	LINDGREN	15353-F	NCK	NCK	

Note:

1. The calibrations are traceable to NML/ROC.

2. NCR : No Calibration Required.

Measurement Uncertainty

The assessed measurement uncertainty with a suitable coverage factor K to ensure 95% confidence level for the normal distribution are shown as below, the values are less than U_{cispr} in table 1 of CISPR 16-4-2.

Equipment	Model Number	Uncertainty Value
LISN	ESH2-Z5	3.1dB
	ENV 4200	2.8dB

2.3 Test Procedures

- a. The EUT was set up per the test configuration figured in the next section of this chapter to simulate the typical usage per the user's manual.
- b. If the EUT is tabletop equipment, it was placed on a non-conducted table with a height of 0.8 meters above the reference ground plane and 0.4 meters from the conducting wall of the shielded room. Also if the EUT is floor-standing equipment, it was placed on a non-conducted support with a height of 12 millimeters above the reference ground plane.
- c. Connect the EUT's power source to the appropriate power mains through the LISN.
- d. All the other peripherals are connected to the 2nd LISN, if any.
- e. The LISN was placed 0.8 meters from the EUT and at least 0.8 meters from other units and other metal planes.
- f. Measure the conducted emissions on each power line (Neutral Line and Line 1 Hot side) of the EUT's power source by using the test receiver connected to the coupling RF output port of LISN.
- g. Rapidly scan the signal from 150kHz to 30MHz by using the receiver through the Maximum-Peak detector to determine those frequencies associated with higher emission levels for each measured line.
- h. Then measure the maximum level of conducted disturbance for each frequency found from step g. by using the receiver through the Quasi-Peak and Average detectors per CISPR 16-1.
- i. Record the level for each frequency and compare with the required limit.

2.4 Test Configurations





2.5 Photographs of the Test Configurations



2.6 Test Results

Test Mode	:	As description of section 1.2				
Test Voltage	:	120V/60Hz to the power adapter				
Tester	:	Kent	Temperature	:	26°C	
Humidity	:	47%RH	Frequency Range	:	150kHz~30MHz	
IF Bandwidth	:	9kHz	Phase	:	Line	



- 1. Emission Level = reading value + correction factor.
- 2. Correction factor = cable loss + insertion loss of LISN.
- 3. Q.P. is abbreviation of quasi-peak.

IF Bandwidth	:	9kHz	Phase	:	Neutral		
Humidity	:	47%RH	Frequency Range	:	150kHz~30MHz		
Tester	:	Kent	Temperature	:	26°C		
Test Voltage	:	120V/60Hz to	120V/60Hz to the power adapter				
Test Mode	:	As description	As description of section 1.2				



- 1. Emission Level = reading value + correction factor.
- 2. Correction factor = cable loss + insertion loss of LISN.
- 3. Q.P. is abbreviation of quasi-peak.

3. Radiated Emission Measurement

Test Result : <u>PASS</u>

3.1 Limits for Emission Measurement

☑ Limits for radiated disturbances below 1000MHz

Frequency	Class A Equipment (10m distance)	Class B Equipment (3m distance)				
(MHz)	Quasi-peak	Quasi-peak				
	(dBµV/m)	(dBµV/m)				
30 to 88	39.1	40				
88 to 216 43.5		43.5				
216 to 960	46.4	46				
960 to 1000	49.5	54				
Note 1- The lower limi Note 2- Additional pro	Note 1- The lower limit shall apply at the transition frequency. Note 2- Additional provisions may be required for cases where interference occurs.					
Note 3- According to 7	Note 3- According to 15.109(g), as an alternative to the radiated emission limits shown above, digital					
devices may be shown to comply with the standards (CISPR), Pub. 22 shown as below.						
30 to 230	40	30				
230 to 1000	47	37				

□ Limits for radiated disturbances in the frequency range 1000MHz ~ 2000MHz at a measuring distance of 10m

Frequency	Class A Ec	quipment	Class B Equipment	
(GHz)	Peak	Average	Peak	Average
(6112)	(dBµV/m)	(dBµV/m)	(dBµV/m)	(dBµV/m)
1 to 2	69.5	49.5	63.5	43.5

☑ Limits for radiated disturbances above 1000MHz at a measuring distance of 3m

Frequency	Class A Ec	quipment	Class B Equipment	
(GHz)	Peak	Average	Peak	Average
	(dBµV/m)	(dBµV/m)	(dBµV/m)	(dBµV/m)
1 to 40	80	60	74	54

3.2 Test Instruments

☑ For Measurement at the distance of 10m

Test Site and Equipment	Manufacturer	Model No./ Serial No.	Last Calibration Date	Calibration Due Date
EMI Test Receiver	R&S	ESCS 30/ 836858/020	Sept. 8, 2011	Sept. 8, 2012
Broadband Antenna	R&S	HL-562/ 360543/007	March 29, 2011	March 29, 2012
Broadband Antenna	R&S	HL-562/ 830547/010	April 26, 2011	April 26, 2012
Pre-Amplifier	Mini Circuit	ZKL-2/ 001	July 18, 2011	Jan. 18, 2012
Pre-Amplifier	Mini Circuit	ZKL-2/ 002	July 18, 2011	Jan. 18, 2012
Spectrum	R&S	FSP7/ 100108	June 10, 2011	June 10, 2012
Spectrum	R&S	FSP7/ 100384	Dec. 23, 2010	Dec. 23, 2011
RF Cable	JYEBAO	0214/ C0049	July 18, 2011	Jan. 18, 2012
RF Cable	JYEBAO	0214/ C0050	July 18, 2011	Jan. 18, 2012
Test Software	Audix	e3/ Ver. 4.3.714.e	NCR	NCR
TR1 Semi - anechoic Chamber	ETS. LINDGREN	TR1/ 17627-B	April 23, 2011	April 23, 2012

- 1. The calibrations are traceable to NML/ROC.
- 2. NCR : No Calibration Required.
- 3. The calibration date of the semi-anechoic chamber listed above is the date of NSA measurement.

☑ For Measurement at the distance of 3m

Test Site and	Manufacturer		Model No./	Last	Calibration
Equipment			Serial NO.		
EMI Test Receiver	R&S		ESCI/ 100019	May 25, 2011	May 25, 2012
Bi-Log Antenna	EMCO		3142C/ 52088	May 19, 2011	May 19, 2012
Horn Antenna	EMCO		3117/ 00082847	March 1, 2011	March 1, 2012
Bore-sight Antenna Mast	Sunol		TLT2/ 051110-5	NCR	NCR
	КМІС		KMA010180A01/ 99056	Oct. 12, 2011	Oct. 12, 2012
	Mini Circuit		ZKL-2/ 004	Aug. 6, 2011	Feb. 6, 2012
т те-дпірішег	MITEQ		JS4-00101800- 28-10P/1498979	Dec.10, 2010	Dec.10, 2011
	MITEQ		JS4-00101800- 28-5A/742229	Dec.15, 2010	Dec.15, 2011
Spectrum Analyzer	Agilent		E4407B/ MY45106795	May 2, 2011	May 2, 2012
RF Cable	N/A		N/A/ C0080	Aug. 6, 2011	Feb. 6, 2012
RF Cable	N/A		N/A/ C0081	Oct. 17, 2011	April 17, 2012
Test Software	Audix		e3/ Ver. 4.3.714.e	NCR	NCR
TR11 Semi - anechoic Chamber	ETS. LINDGREN		TR11/ 906-A	April 17, 2011	April 17, 2012

- 1. The calibrations are traceable to NML/ROC.
- 2. NCR : No Calibration Required.
- 3. The calibration date of the semi-anechoic chamber listed above is the date of NSA measurement.

Measurement Uncertainty

The assessed measurement uncertainty with a suitable coverage factor K to ensure 95% confidence level for the normal distribution are shown as below, the values are less than U_{cispr} in table 1 of CISPR 16-4-2.

Test Site	Polarization	Frequency Range			
(Measuring distance)	r olarization	30MHz ~200MHz	200MHz ~1000MHz		
TR1(10m)	Horizontal	3.5dB	3.9dB		
	Vertical	3.5dB	3.9dB		
TR11(3m)	Horizontal	3.5dB	3.9dB		
	Vertical	3.8dB	3.9dB		

Test Site	Polarization	Frequency Range			
(Measuring distance)	r olanzation	1GHz ~18GHz	18GHz~26GHz		
TR11(3m)	Horizontal	3.5dB	4.4dB		
	Vertical	3.6dB	4.5dB		

3.3 Test Procedures

- a. The EUT was set up per the test configuration figured in the next section of this chapter to simulate the typical usage per the user's manual.
- b. If the EUT is tabletop equipment, it was placed on a non-conducted table with a height of 0.8 meters above the reference ground plane in the semi-anechoic chamber. If the EUT is floor-standing equipment, it was placed on a non-conducted support with a height of 12 millimeters above the reference ground plane in the semi-anechoic chamber.
- c. For the measurement of frequency below 1000MHz, the EUT was set 10m away from the interference receiving antenna for the limit of Class A equipment or CISPR 22. For Class B equipment and the measurement of frequency above 1000MHz, the EUT was set 3m away from the interference receiving antenna.
- d. Rapidly sweep the signal in the test frequency range by using the spectrum through the Maximum-peak detector.
- e. Rotate the EUT from 0° to 360° and position the receiving antenna at heights from 1 to 4 meters above the reference ground plane continuously to determine at least six frequencies associated with higher emission levels and record them.
- f. For measurement of frequency above 1000MHz, the beamwidth of receiving horn antenna should keep covering EUT when the receiving horn antenna height varied.
- g. Then measure each frequency found from step e. by using the spectrum with rotating the EUT and positioning the receiving antenna height to determine the maximum level.
- h. Finely tune the antenna and turntable around the recorded position of each frequency found from step f.
- i. For measurement of frequency below 1000MHz, set the receiver detector to be Quasi-Peak per CISPR 16-1 to find out the maximum level occurred.
- j. For measurement of frequency above 1000MHz, set the spectrum detector to be Peak or Average to find out the maximum level occurred, if any.
- k. Record frequency, azimuth angle of the turntable, height, and polarization of the receiving antenna and compare the maximum level with the required limit.
- I. Change the receiving antenna to another polarization to measure radiated emission by following step d. to k. again.
- m. If the peak emission level measured from step e. is 4dB lower than the limit specified, then the emission values presented will be the peak value only. Otherwise, accurate Q.P. value will be measured and presented.

3.4 Test Configurations

Radiated Emission Measurement below 2000MHz



Radiated Emission Measurement above 1000MHz (if any)





3.5 Photographs of the Test Configurations



3.6 Test Results

Radiated Emission Measurement below 1000MHz

IF Bandwidth	:	120kHz	Polarization	:	Horizontal				
Humidity	:	63%RH	Frequency Range	:	30MHz~1GHz				
Tester	:	Meng Lin	Temperature	:	23°C				
Test Voltage	:	120V/60Hz to	120V/60Hz to the power adapter						
Test Mode	:	As description of section 1.2							



- 1. Emission Level = reading value + correction factor.
- 2. Correction factor = cable loss + antenna factor gain of pre-amplifier.
- 3. Q.P is abbreviation of quasi-peak.

Test Mode	:	As description of section 1.2							
Test Voltage	:	120V/60Hz to	120V/60Hz to the power adapter						
Tester	:	Meng Lin	Temperature	:	23°C				
Humidity	:	63%RH	Frequency Range	:	30MHz~1GHz				
IF Bandwidth	:	120kHz	Polarization	:	Vertical				



- 1. Emission Level = reading value + correction factor.
- 2. Correction factor = cable loss + antenna factor gain of pre-amplifier.
- 3. Q.P is abbreviation of quasi-peak.

Radiated Emission Measurement above 1000MHz

IF Bandwidth	:	1MHz	Polarization	:	Horizontal				
Humidity	:	63%RH	Frequency Range	:	1GHz ~9GHz				
Tester	:	Carl Yan	Temperature	:	23°C				
Test Voltage	:	120V/60Hz to	20V/60Hz to the power adapter						
Test Mode	:	As description	As description of section 1.2						



	-								-	
	Mz	dBuV/m	dBu∛	dB/m	dBuV/m	dB	 	deg		
1	1088.360	47.40	88.50	-41.10	80.00	-32.60	108	148	HORI ZONTAL	Peak
2 @	1089.460	32.68	73.78	-41.10	60.00	-27.32	109	149	HORI ZONTAL	Average
3	1232.260	45.60	86.68	-41.08	80.00	-34.40	158	309	HORI ZONTAL	Peak
4	1233.370	32.57	73.65	-41.08	60.00	-27.43	159	310	HORI ZONTAL	Average
5	1328.630	41.78	82.92	-41.14	80.00	-38.22	127	165	HORI ZONTAL	Peak
6	1329.350	32.44	73.58	-41.14	60.00	-27.56	128	166	HORI ZONTAL	Average

- 1. Emission Level = reading value + correction factor.
- 2. Correction factor = cable loss + antenna factor gain of pre-amplifier.

IF Bandwidth	:	1MHz	Polarization	:	Vertical				
Humidity	•	63%RH	Frequency Range		1GHz ~9GHz				
Tester	:	Carl Yan	Temperature	:	23°C				
Test Voltage	:	120V/60Hz to	120V/60Hz to the power adapter						
Test Mode	:	As description of section 1.2							



	Freq	Level	Read Level	Factor	Limit Line	Over Limit	Ant Pos	Table Pos	Pol/Phase	Remark
	Mrz	dBuV/m	dBuV	dB/m	dBuV/m	dB	cm	deg		
1	1328.270	49.23	90.37	-41.14	80.00	-30.77	137	34	VERTICAL	Peak
2 @	1329.340	41.53	82.67	-41.14	60.00	-18.47	136	33	VERTICAL	Average
3 @	1928.780	53.01	90.33	-37.32	80.00	-26.99	152	155	VERTICAL	Peak
40	1929.420	42.27	79.59	-37.32	60.00	-17.73	151	156	VERTICAL	Average
5	2408.530	50.23	86.05	-35.82	80.00	-29.77	116	108	VERTICAL	Peak
6 @	2409.530	39.86	75.68	-35.82	60.00	-20.14	117	109	VERTICAL	Average

- 1. Emission Level = reading value + correction factor.
- 2. Correction factor = cable loss + antenna factor gain of pre-amplifier.

Attachment 1 Photographs of EUT













Attachment 2 Modifications of EUT

Statement of the EUT Modifications

According to the rules of ANSI C63.4-2003 clause 10.1.13, the following equipment (EUT):

Product	:	Fanless Touch Panel
Model No.	:	xxxxxAHP-2122HTT –xxxxxxxx
		(Where x is 0-9 , A-Z , -or blank) for marketing purpose
Manufacturer	:	AAEON Technology Inc.
Address	:	5F,NO.135,Lane 235,Pao Chiao Rd. Hsin-Tien Dist,New
		Taipei City,Taiwan,R.O.C

□ should be <u>without</u> any modifications made

 \Box should be <u>with</u> some modifications made

to bring the EUT into compliance with the appropriate specifications (47CFR Part 15, Subpart B). If any, the details of the modifications including the complete descriptions, reasons and so on are described in next page of this report.

We , <u>AAEON Technology Inc.</u> hereby ensure that the product specified above will have all of the modifications incorporated in the product when manufactured and placed on the market.

The following importer or manufacturer is responsible for this statement:

Company Name		
Company Address	:	
Telephone	:	E-mail :

Legal Signature of the responsible personal:

Title / Name (full name)

The details of the modifications:

Item	Solution Component	Specifications	Manufacturer	Quantity	Reasons
1					
2					
3					
4					
5					
6					
7					
8					
9					
10					
11					
12					
13					
14					
15					

If needed, some modification items are shown in the photographs in the following.